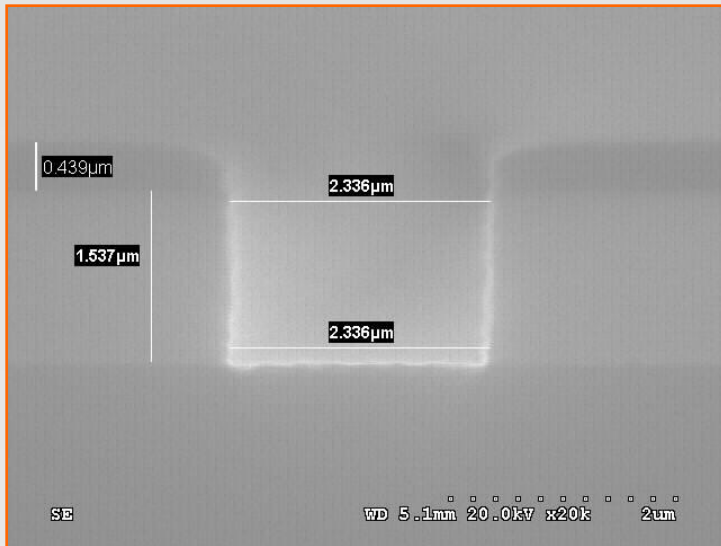


Dielectric Etching Applications

Oxide mask opening



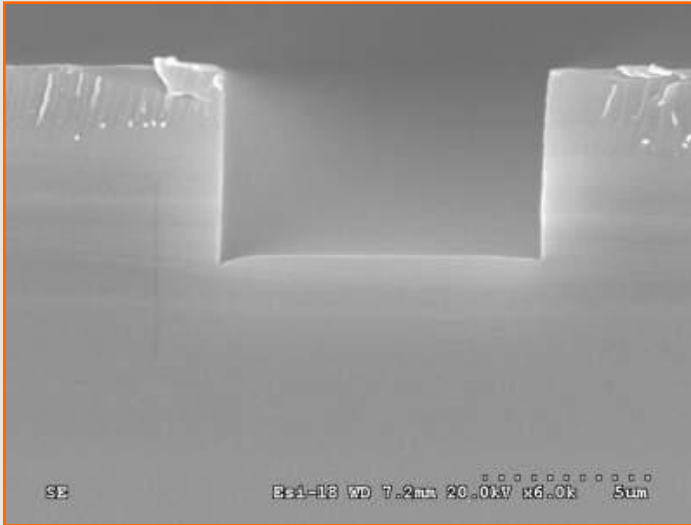
> Conditions

- > Wafer size : 100 mm
- > Feature width : 2.5 μm
- > Etch depth : 1.5 μm
- > Feature shape : Trench
- > Mask : PR
- > Substrate : Si

> Results

- > Etch rate : 0.15 $\mu\text{m}/\text{min}$
- > Selectivity : 2
- > uniformity : +/- 5%
- > profile angle : 90° +/- 1°

Thermal Oxide etching



Fast etch rate
0.9 $\mu\text{m}/\text{min}$

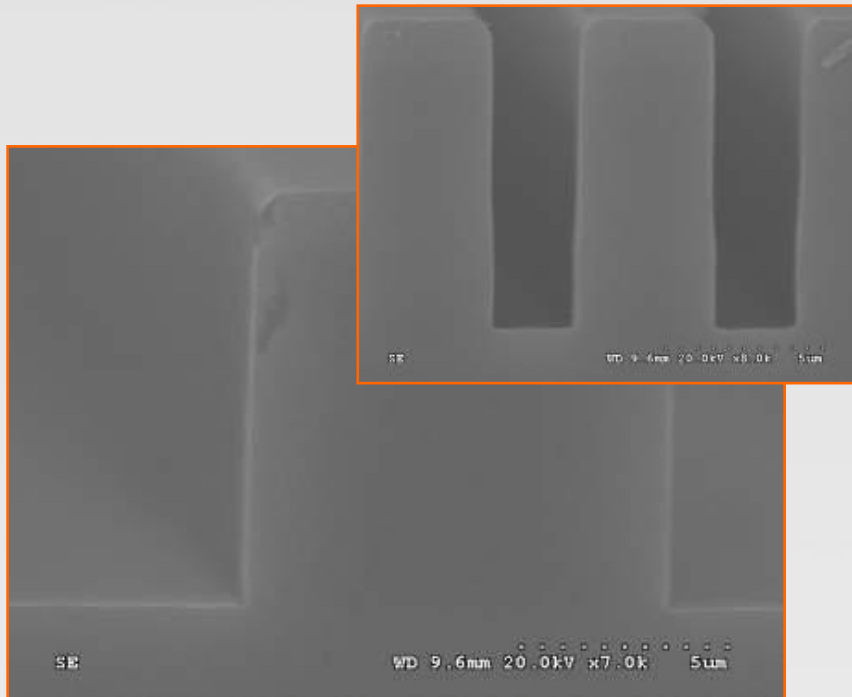
> Conditions

- > Wafer size : 100 mm
- > Feature width : 10 μm
- > Etch depth : 3 μm
- > Feature shape : Trench
- > Mask : PR
- > Substrate : Si

> Results

- > **Etch rate** : **0.9 $\mu\text{m}/\text{min}$**
- > Selectivity : 1.5
- > Slope : 91°

Vertical Oxide etch



Vertical oxide etch

> Conditions

- > Wafer size : 100 mm
- > Feature width : 100 μm
- > Etch depth : 9 μm
- > Feature shape : Trench
- > Mask : Si
- > Substrate : Si

> Results

- > Etch rate : 0.56 $\mu\text{m}/\text{min}$
- > Selectivity : 15
- > **Slope** : **90-91°**

Vertical Oxide etch



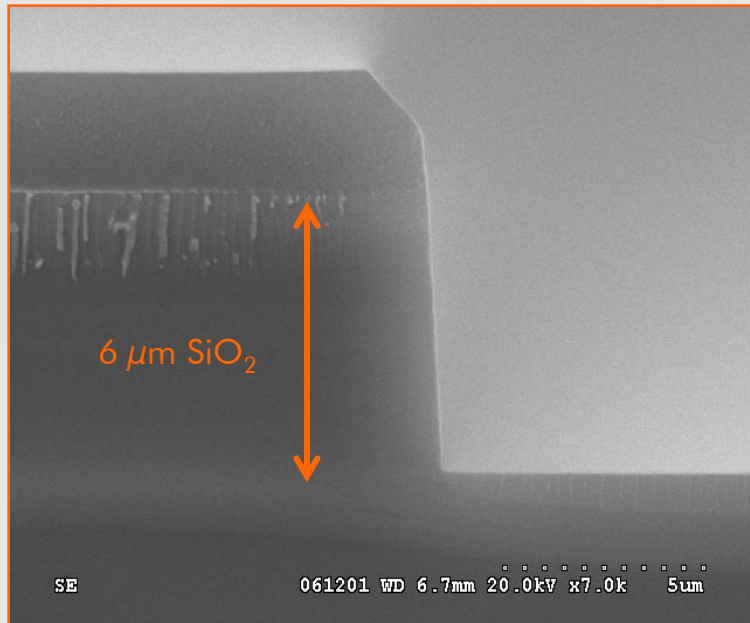
> Conditions

- > Wafer size : 150 mm
- > Feature width : 5 μm
- > Etch depth : 6 μm
- > Feature shape : Trench
- > Mask : PR
- > Substrate : Si

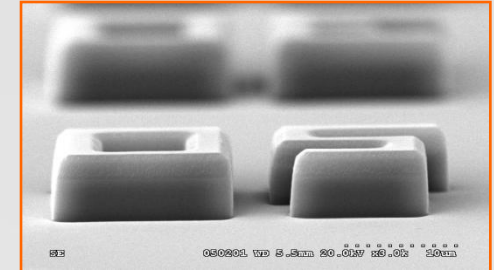
> Results

- > Etch rate : 0.33 $\mu\text{m}/\text{min}$
- > Selectivity : 8
- > Slope : 92.1°

SiO₂ etching with negative PR mask



Etch stop on Si layer, with 5 min over-etch.



> Conditions

- > Wafer size : 100 mm
- > Feature width : 50 μm
- > Etch depth : 6 μm
- > Mask : neg. Photoresist

> Results

- > Selectivity : 10
- > Etch rate : 0.5 μm/min
- > Over etch time : 5 min
- > Uniformity : +/- 2%
- > Profile angle : 91°

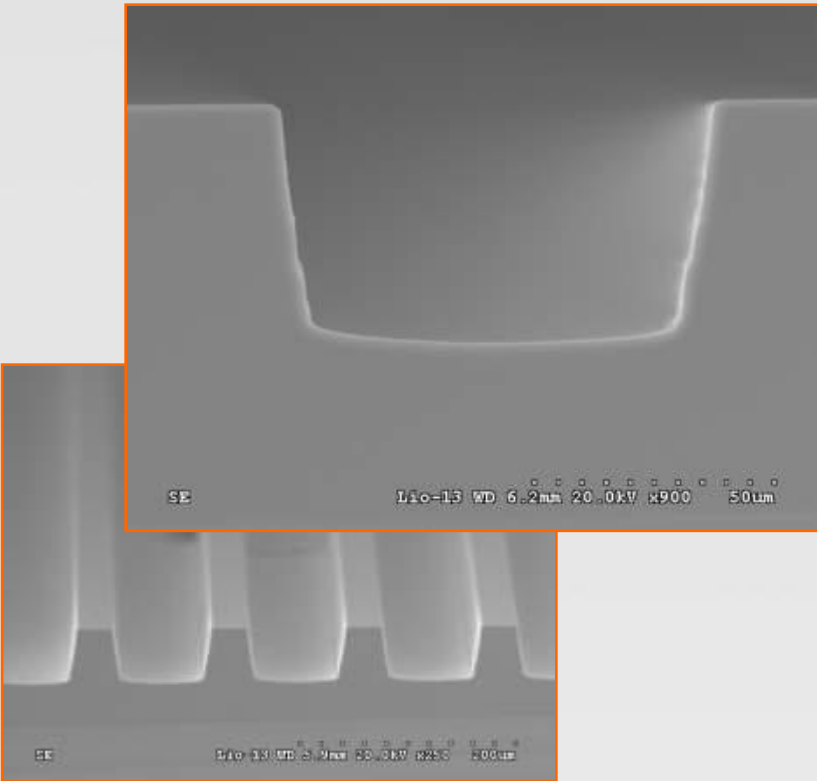
Borosilicate etching

> Conditions

- > Wafer size : 100 mm
- > Feature width : 70 μm
- > Etch depth : 47 μm
- > Feature shape : Trench
- > Mask : Si
- > Substrate : Borosilicate

> Results

- > Etch rate : 0.39 $\mu\text{m}/\text{min}$
- > Selectivity : 18
- > **Slope** : **98°**



Borosilicate etching
Tapered etch with smooth bottom

Buried Oxide etch



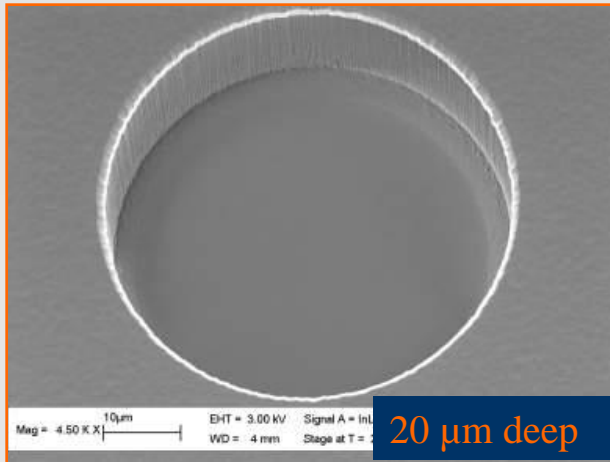
Si etch

SiO2 etch

> Conditions

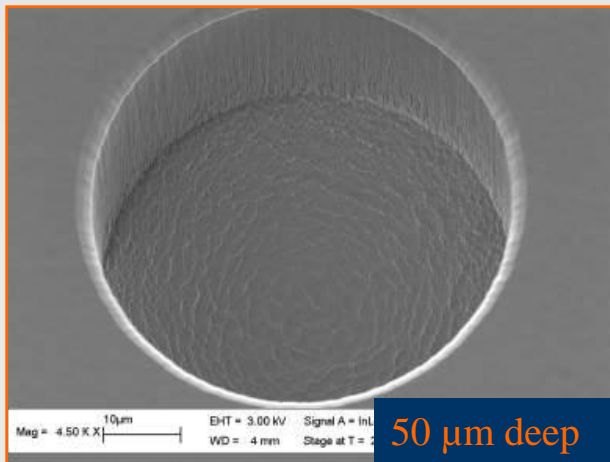
- > Wafer size : 150 mm
- > Feature width : 5 μm
- > Si thickness : 22 μm
- > SiO2 Etch depth : 1.5 μm
- > Feature shape : Trench
- > Mask : PR
- > Substrate : Si

Fused silica etching



> Conditions

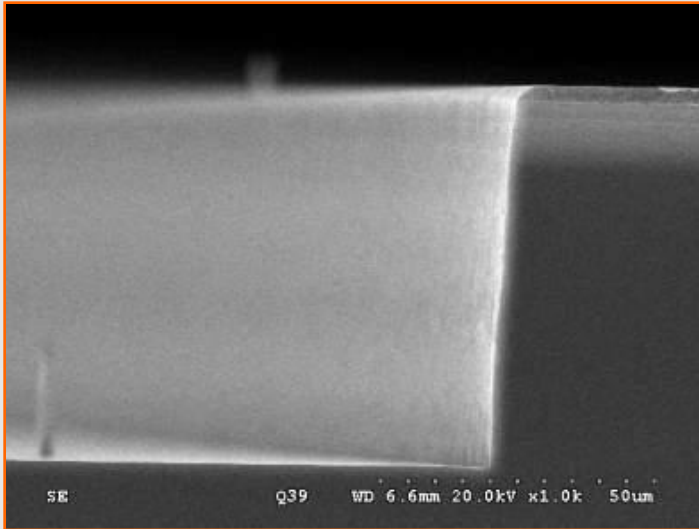
- > Wafer size : 100 mm
- > Feature width : 50 µm
- > Feature shape : Hole
- > Mask : Si
- > Substrate : Fused Silica



> Results

- > Etch rate : 0.43 µm/min
- > Etch depth : 20 µm to 50µm

Fused silica etching



Fused Silica
66 μm deep

> Conditions

- > Wafer size : 100 mm
- > Feature width : 500 μm
- > Feature shape : Trench
- > Mask : Si
- > Substrate : Fused Silica

> Results

- > Etch rate : **0.44 $\mu\text{m}/\text{min}$**
- > Selectivity : 40
- > Etch depth : **66 μm**

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